

HX251 Hall-effect sensor is a temperature stable, stress-resistant, Low Tolerance of Sensitivity micro-power switch. Superior high-temperature performance is made possible through a dynamic offset cancellation that utilizes chopper-stabilization. This method reduces the offset voltage normally caused by device over molding, temperature dependencies, and thermal stress.

HX251 is special made for low operation voltage, 1.65V, to active the chip which is includes the following on a single silicon chip: voltage regulator, Hall voltage generator, small-signal amplifier, chopper stabilization, Schmitt trigger, CMOS output driver. Advanced CMOS wafer fabrication processing is used to take advantage of low-voltage requirements, component matching, very low input-offset errors, and small component geometries. This device requires the presence of omni-polar magnetic fields for operation.

The package type is in a Halogen Free version has been verified by third party Lab.

#### Features and Benefits

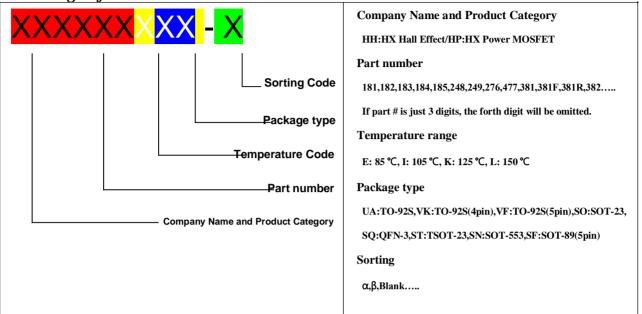
- CMOS Hall IC Technology
- Strong RF noise protection
- 1.65 to 6V for battery-powered applications
- Omni polar, output switches with absolute value of North or South pole from magnet
- Operation down to 1.65V, Micro power consumption
- High Sensitivity for reed switch replacement applications
- Multi Small Size option
- Low sensitivity drift in crossing of Temp. range
- Ultra Low power consumption at 5uA (Avg)
- High ESD Protection, HMB  $> \pm 4$ KV( min )
- Totem-pole output

#### **Applications**

- Solid state switch
- Handheld Wireless Handset Awake Switch (Flip Cell/PHS Phone/Note Book/Flip Video Set)
- Lid close sensor for battery powered devices
- Magnet proximity sensor for reed switch replacement in low duty cycle applications
- Water Meter
- Floating Meter
- PDVD
- NB



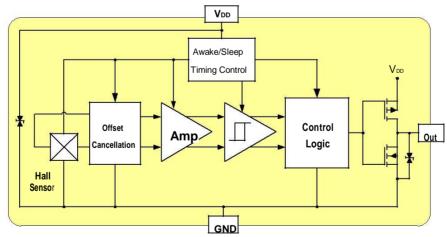
**Ordering Information** 



Part No.	Temperature Suffix	Package Type	
HX251EST	E $(-40^{\circ}\text{C to} + 85^{\circ}\text{C})$	ST (TSOT-23)	
HX251ESN	E $(-40^{\circ}\text{C to} + 85^{\circ}\text{C})$	SN (SOT-553)	
HX251ESQ	E $(-40^{\circ}\text{C to} + 85^{\circ}\text{C})$	SQ (QFN2020-3)	
HX251KUA	K (-40°C to + 125°C)	UA (TO-92S)	

Custom sensitivity selection is available by HX sorting technology

### Functional Diagram



Note: Static sensitive device; please observe ESD precautions. Reverse  $V_{DD}$  protection is not included. For reverse voltage protection, a  $100\Omega$  resistor in series with  $V_{DD}$  is recommended.

HX 251,  $HBM > \pm 4KV$  which is verified by third party lab.



Absolute Maximum Ratings At(Ta=25°C)

Characteristics		Values	Unit
Supply voltage,(VDD)		4.5	V
Output Voltage,(Vout)		4.5	V
Reverse Voltage, (VDD) (VOUT)		-0.3	V
Magnetic flux density		Unlimited	Gauss
Output current,(IovT)		1	mA
Operating temperature range, (Ta)		-40 to +85	°C
Storage temperature range, $(Ts)$		-65 to +150	°C
Maximum Junction Temp, $(Tj)$		150	°C
Thermal Resistance	$(\theta_{JA})$ ST / SN / UA / SQ	310 / 540 / 206 / 543	°C/W
	$(\theta_{JC})$ ST / SN / UA / SQ	223 / 390 / 148 / 410	°C/W
Package Power Dissipation, $(P_D)$ ST/SN/UA/SQ		400 / 230 / 606 / 230	mW

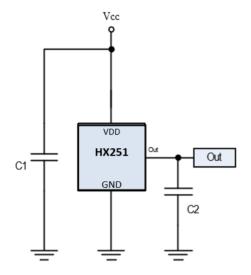
**Note:** Exceeding the absolute maximum ratings may cause permanent damage. Exposure to absolute maximum-rated conditions for extended periods may affect device reliability.

### **Electrical Specifications**

DC Operating Parameters : Ta=25 °C,  $V_{DD}=1.8V$ 

Paramete	rs	<b>Test Conditions</b>	Min	Тур	Max	Units
Supply Voltage, (VDI	o)	Operating	1.65		6	V
Supply Current,(IDD)		Awake State		1.4	3	mA
		Sleep State		3.6	7	μΑ
		Average		5	10	μΑ
Output Leakage Current,(Ioff)		Output off			1	uA
Output High Voltage,(VOH)		Iout=0.5mA(Source)	V <sub>DD</sub> -0.2			V
Output Low Voltage,(Vol)		Iout=0.5mA(Sink)			0.2	V
Awake mode time,( <i>Taw</i> )		Operating		40	80	uS
Sleep mode time,(Ts	SL)	Operating		40	80	mS
Duty Cycle, $(D,C)$				0.1		%
Electro-Static Disch	arge	HBM	4			KV
Operate Point,	$(B_{OPS})$	S pole to branded side, B > BOP, Vout On		30	55	Gauss
	$(B_{OPN})$	N pole to branded side, B > BOP, Vout On	-55	-30		
Release Point	$(B_{RPS})$	S pole to branded side, B < BRP, Vout Off	10	20		Gauss
	$(B_{RPN})$	N pole to branded side, B < BRP, Vout Off		-20	-10	
Hysteresis,(BHYS)		BOPx - BRPx		10		Gauss

### Typical Application circuit

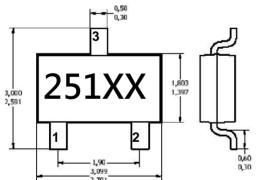


C1: 10nF

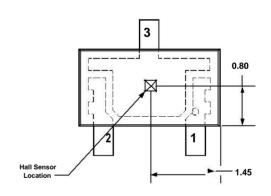
C2: 100pF

# Sensor Location, package dimension and marking MH251 Package

ST Package(TSOT-23)
(Top View)



# Hall Plate Chip Location (Bottom view)



#### **NOTES:**

1. PINOUT (See Top View at left:)

Pin 1 VDD

Pin 2 Output

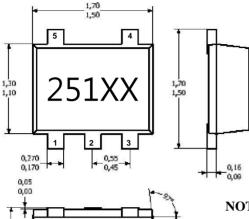
Pin 3 GND

2. Controlling dimension: mm;



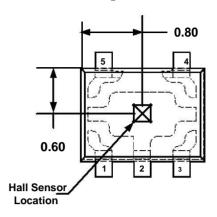
#### SN Package (SOT-553)

(Top View)



#### **Hall Plate Chip Location**

(Top View)



#### **NOTES:**

1. PINOUT (See Top View at left:)

Pin 1 NC

Pin 2 GND

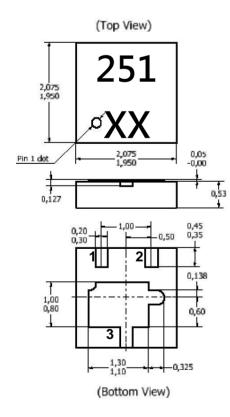
Pin 3 NC

Pin 4 V<sub>DD</sub>

Pin 5 Out

2. Controlling dimension: mm;

#### **SQ Package**



#### NOTES:

PINOUT (See Top View at left)

Pin 1 VDD

Pin 2 Output

Pin 3 GND

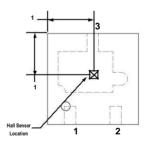
 Controlling dimension: mm;

5. Chip rubbing will be 10mil maximum;

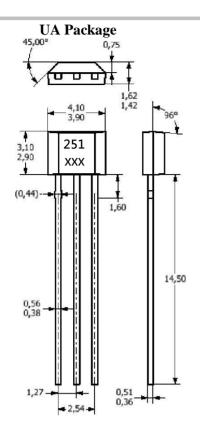
6. Chip must be in PKG. center.

Hall Plate Chip Location

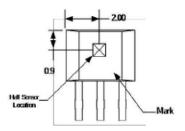
(Top view)



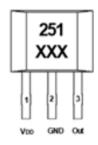




#### **Hall Chip location**



Output Pin Assignment (Top view)



#### **NOTES:**

- 1).Controlling dimension: mm
- 2).Leads must be free of flash and plating voids
- 3).Do not bend leads within 1 mm of lead to package interface.
- 4).PINOUT:

Pin 1 VDD

Pin 2 GND

Pin 3 Output